



FAIR

Facility for Antiproton and Ion Research

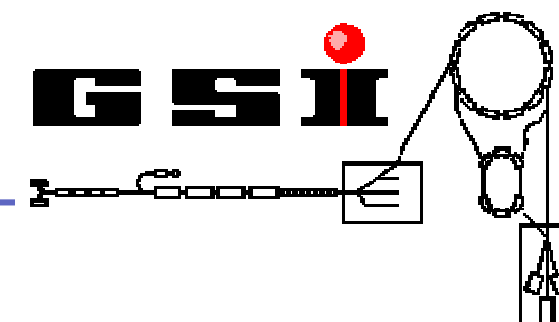


Status of the n-XYTER and CBM-XYTER development line

Christian J. Schmidt et al.,
GSI Darmstadt



GSI, Darmstadt, Feb. 11th 2009



n-XYTER: Novel FE-Chip Architecture Cast in Silicon

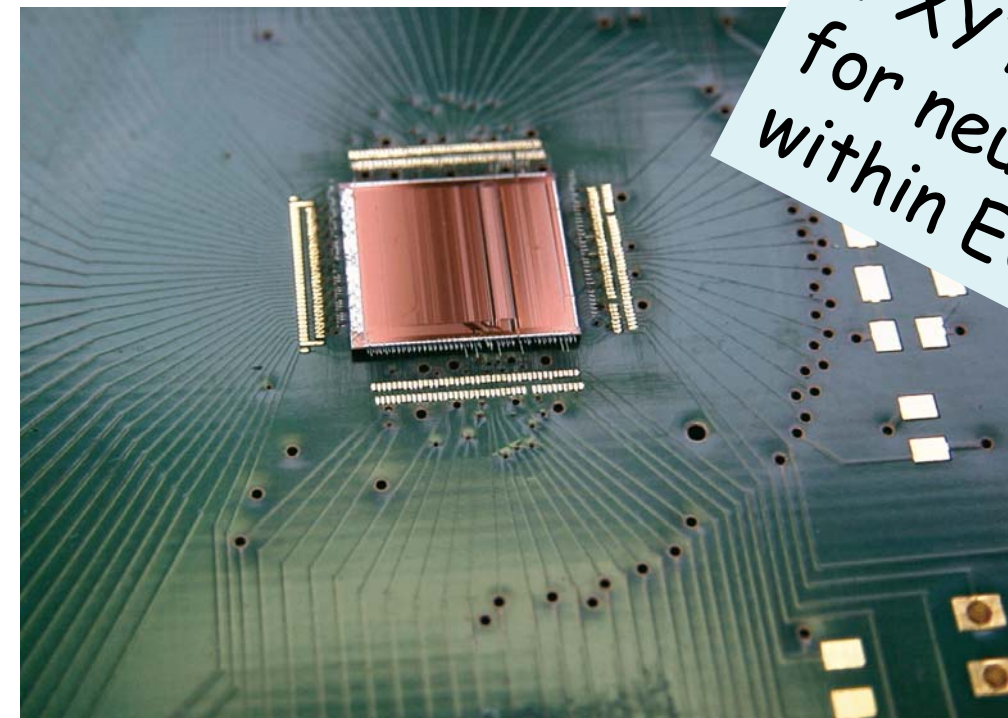
Architectural Solution for FAIR CBM and PANDA.

Starting point towards a FAIR dedicated XYTER front-end ASIC

Our work-horse readout ASIC for detector prototyping

detector readout ASIC for high-density and high statistical rate time and amplitude measurement

- 128 channels @ 50.7 μ pitch
- freely running, self triggered, autonomous hit detection
- 850 (1000) ENC at 30 pF
- dynamic range for 6 MIPs (300 μ Si)
- positive and negative signals
- Per channel analogue energy and digital time stamp FIFO (1ns resolution)
- De-randomizing, sparsifying Token Ring readout at 32 MHz



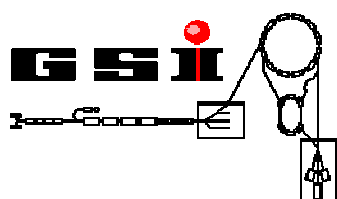
n-XYTER was developed for neutron applications within EU FP-6 NMI3

nmi3



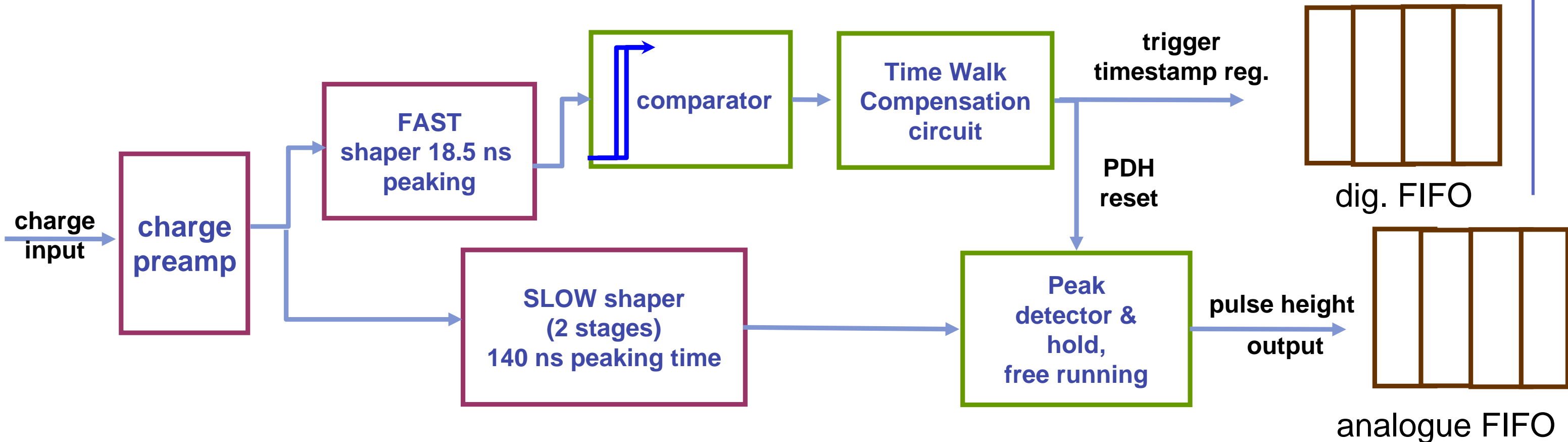
n-XYTER, current workhorse chip for detector prototyping

- architectural example front-end for DAQ development
 - self triggered autonomous hit detection,
 - sparcifying, synchronous readout through token-ring
- sample ASIC for technological front-end electronics hybrid developments
 - bonding technology, circuit board technology
 - thermal management, active cooling concepts
 - power management
(integrally high currents, low voltage, high B-fields, high rad. environment)
 - very dense mechanical boundary conditions

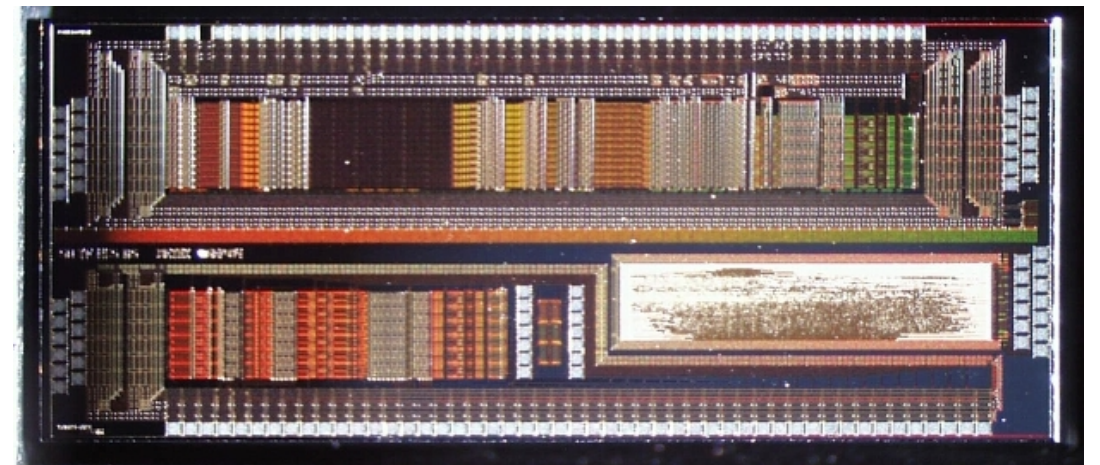


Data Driven Front-End: Asynchronous Channel Trigger

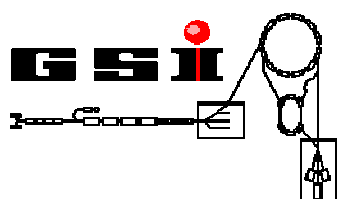
detection of statistical, poisson distributed signals



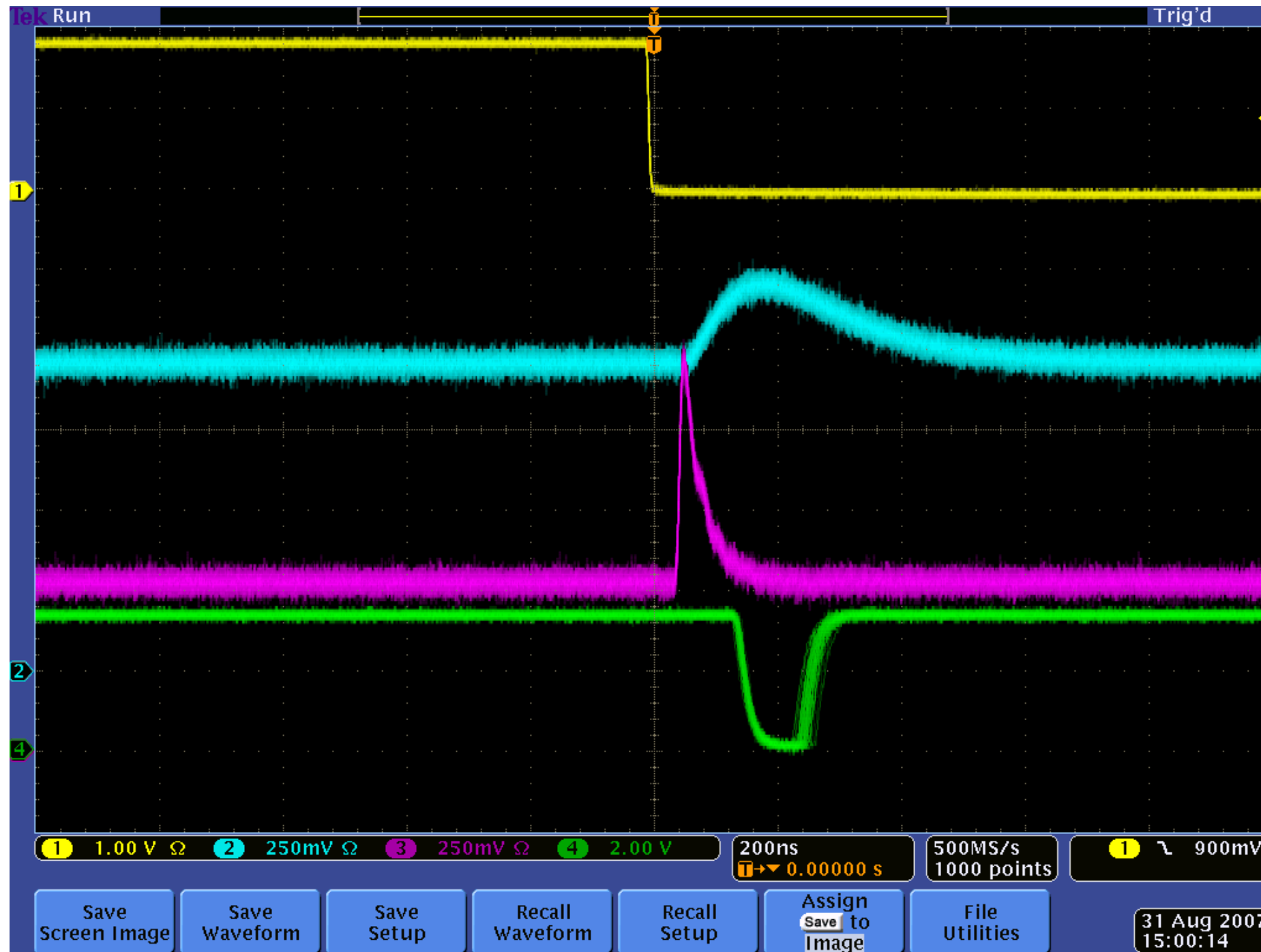
Asynchronous registry and storage in 4-level fifo guarantees data loss < 4 % when read-out through token ring



The DETNI ASIC 1.0, a front-end evaluation chip in AMS 0.35μ



Analogue Signal Sequence (Test Channel)

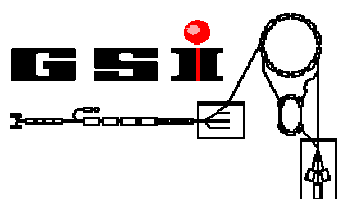


Testpulse Release

Slow Shaper

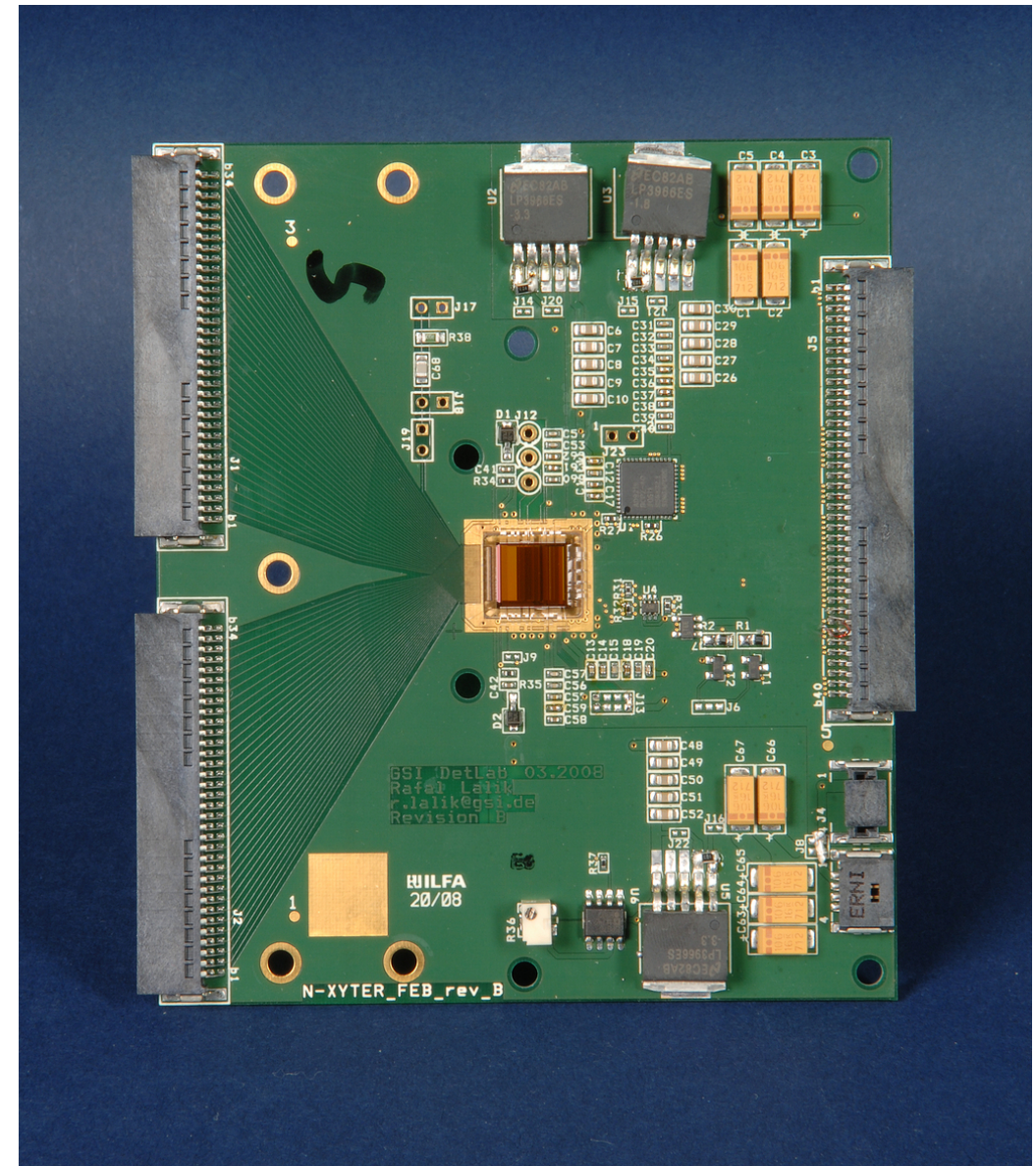
Fast Shaper

Discriminator Output



"Simple" FEB for the n-XYTER Starter Kit

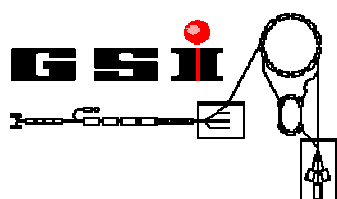
- A simple hybrid PCB with signal fan-in, ADC and interconnect to SysCore DAQ chain
- Allow development of the DAQ chain
- Allow the readout of various detector prototypes
- Allow to explore the challenges of hybrid development



The September beam time has shown the whole signal chain operative!

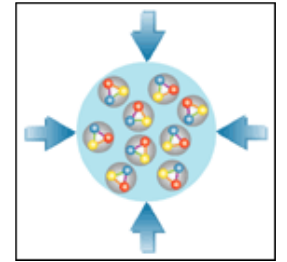
Silicon Strip / GEM Gas Detectors --- n-XYTER --- SysCore DAQ System

Currently 10 FEBs available!

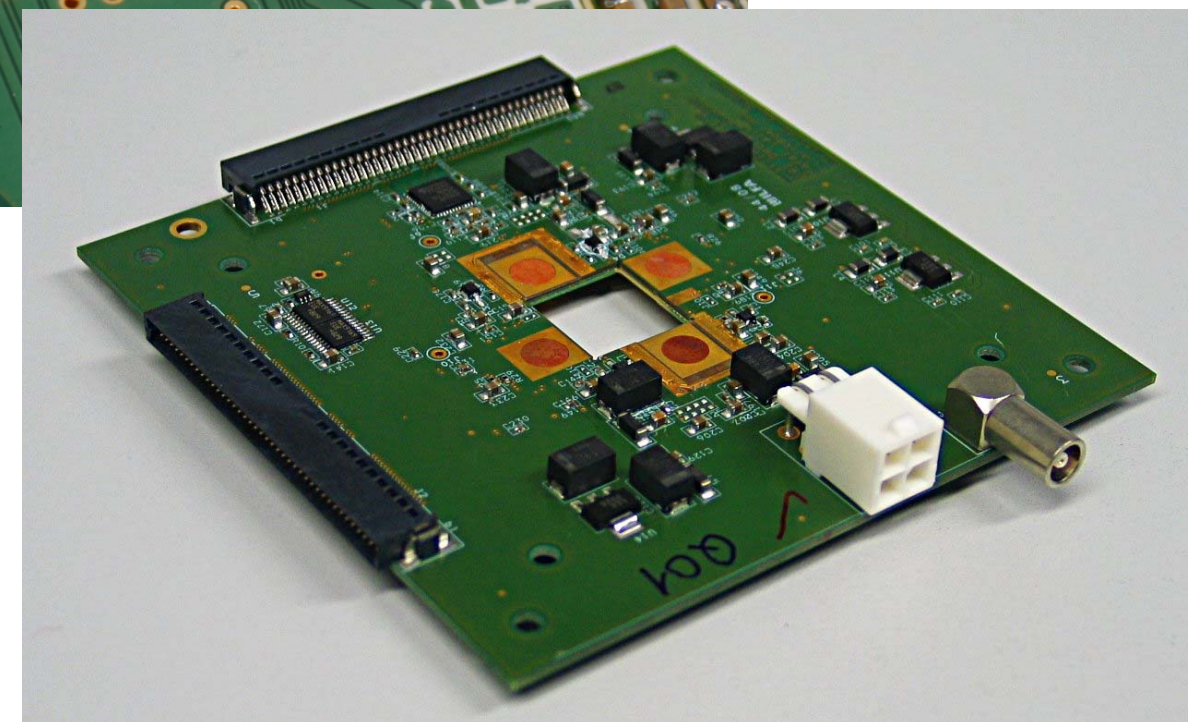
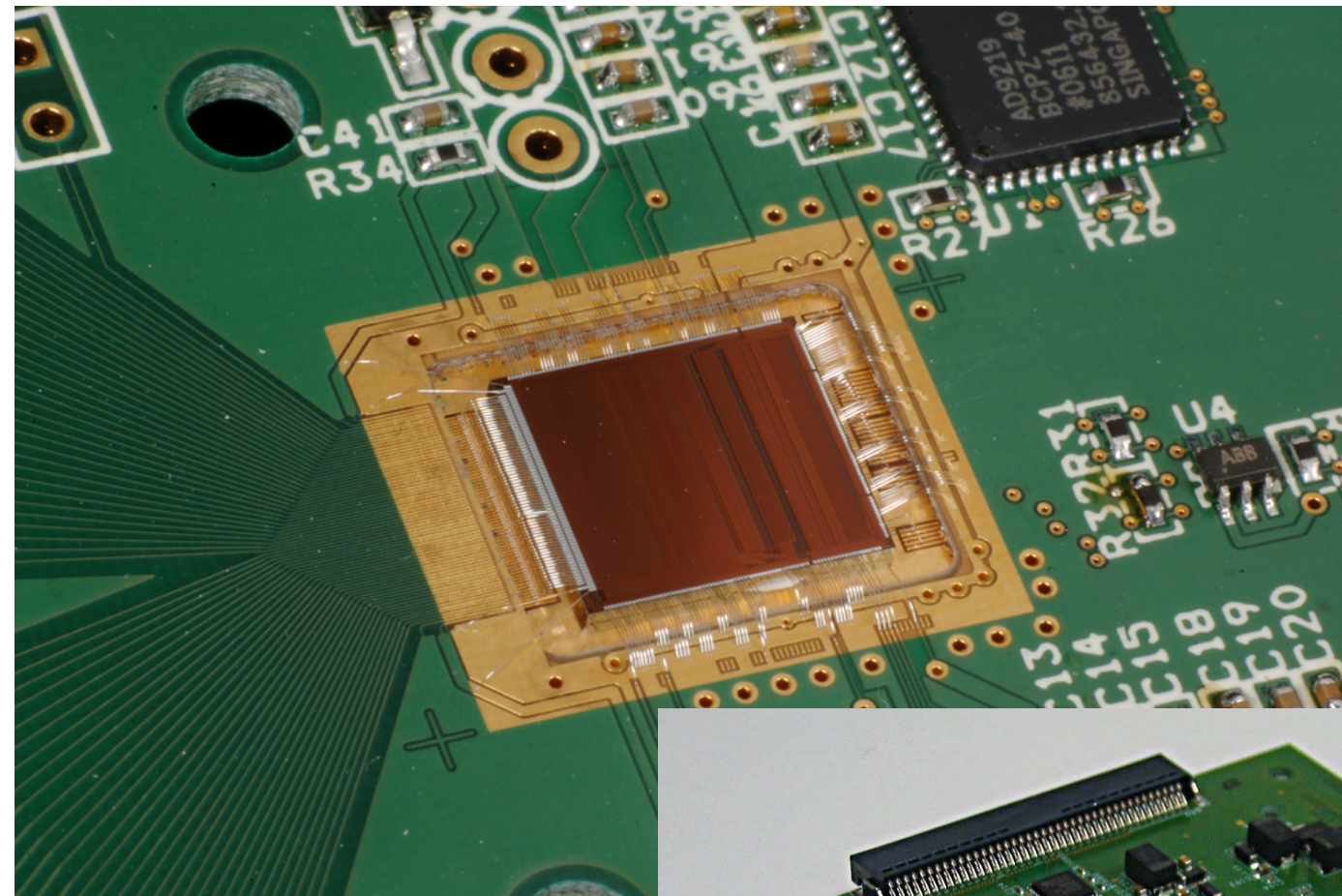


n-XYTER FEB: At the limits of PCB-technology

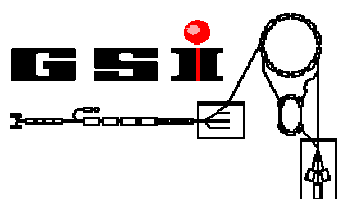
Interference point of several technologies,
each imposing limiting boundary conditions:



- Chip-In-Board solution avoids space eating vias
- allows pitch adaptation:
 - 50,7 μm on chip to
 - PCB side 101,4 μm on two levels

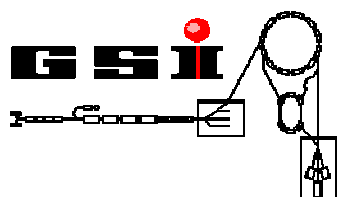
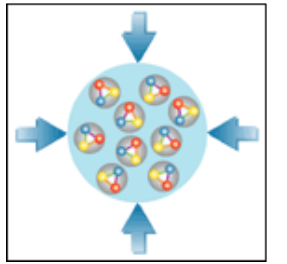


- 4-chip Silicon strip detector test board



STS specific hybrid developments

- Hybrid for STS Silicon Detector Ladder Modules
- Combined challenges of
 - high density chip assembly needs
 - sensitive micro-cable detector interconnect
 - integrated cooling
 - integrated powering scheme in high magnetic fields and rad. env.
- Tentatively, a completely different technology comes into play:
 - Silicon based circuit board
 - flip-chip assembly of XYTERs
 - high efficiency cooling contacts and hybrid stackability
 - tap-bonding for micro-cables (V. Pugatch, Kiev)

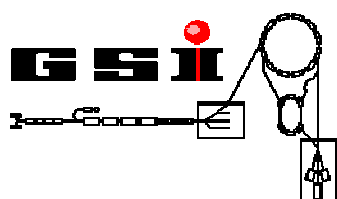


Activities in Heidelberg: Preparation of n-XYTER engineering run

An Engineering Run of the n-XYTER will supply us with chips for detector prototyping activities!

Towards this production, some issues may be addressed.

- n-XYTER prototype showed a large temp. coeff. due to unmatched circuitry assembled from different labs (DETNI collaboration). The correction of it is the major modification currently realized.
 - A process more suited for mixed signal designs will be employed
 - Rearranged bond-pad lay-out will facilitate bonding
 - Enhanced on-chip shielding will inhibit cross-talk and inter circuit feed-back
 - two versions of dynamic range (120 000 e, 1000 000 e) will widen scope of applications

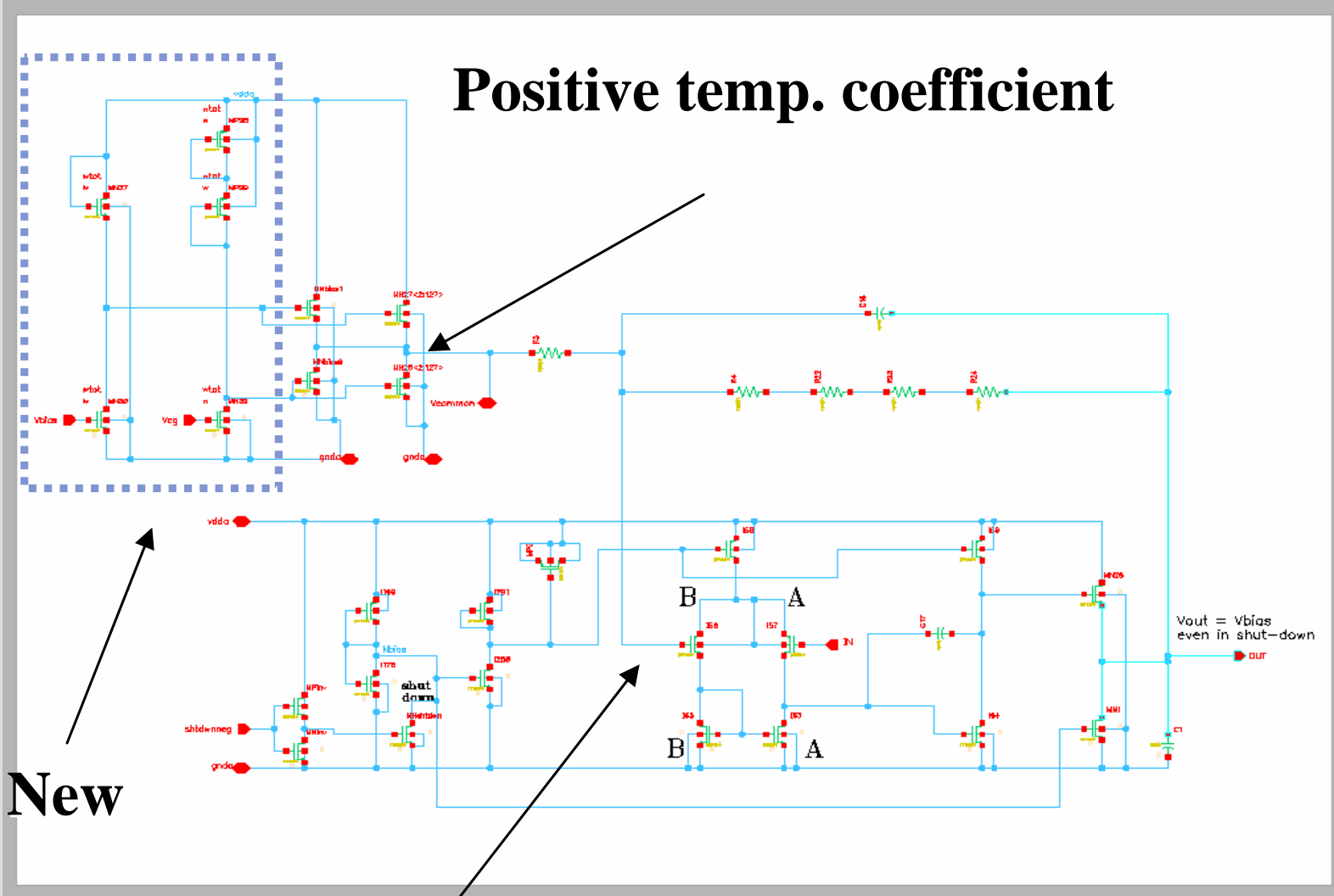


TEMPERATURE SENSITIVITY

Additional compensating circuitry added to undo former TC-mismatch

FAST SHAPER Reworked (preliminary)

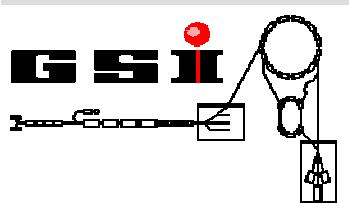
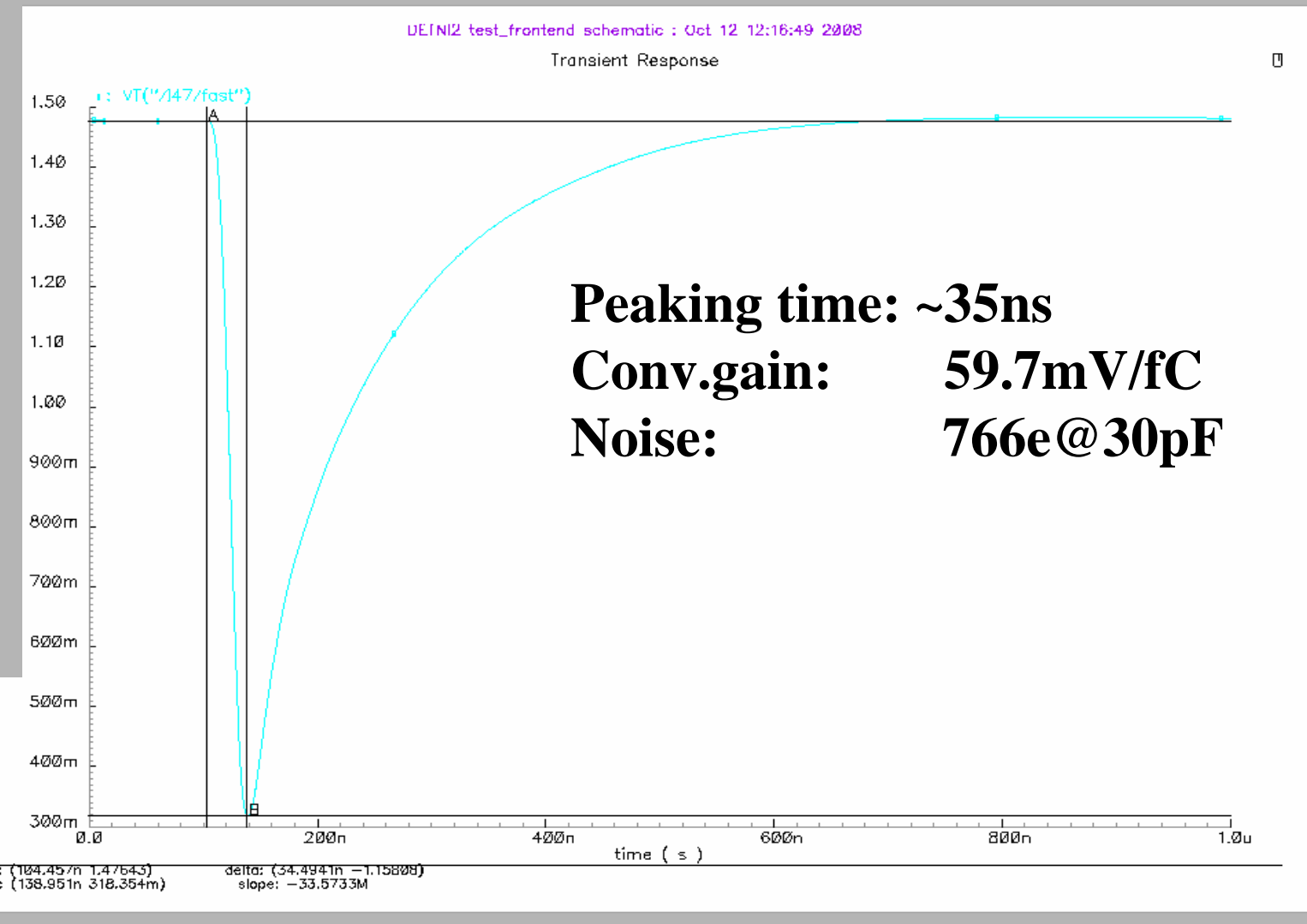
Positive temp. coefficient



New

Negative temp. coefficient

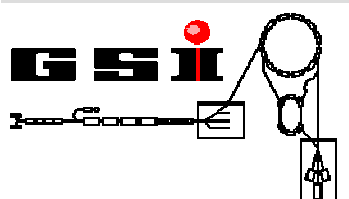
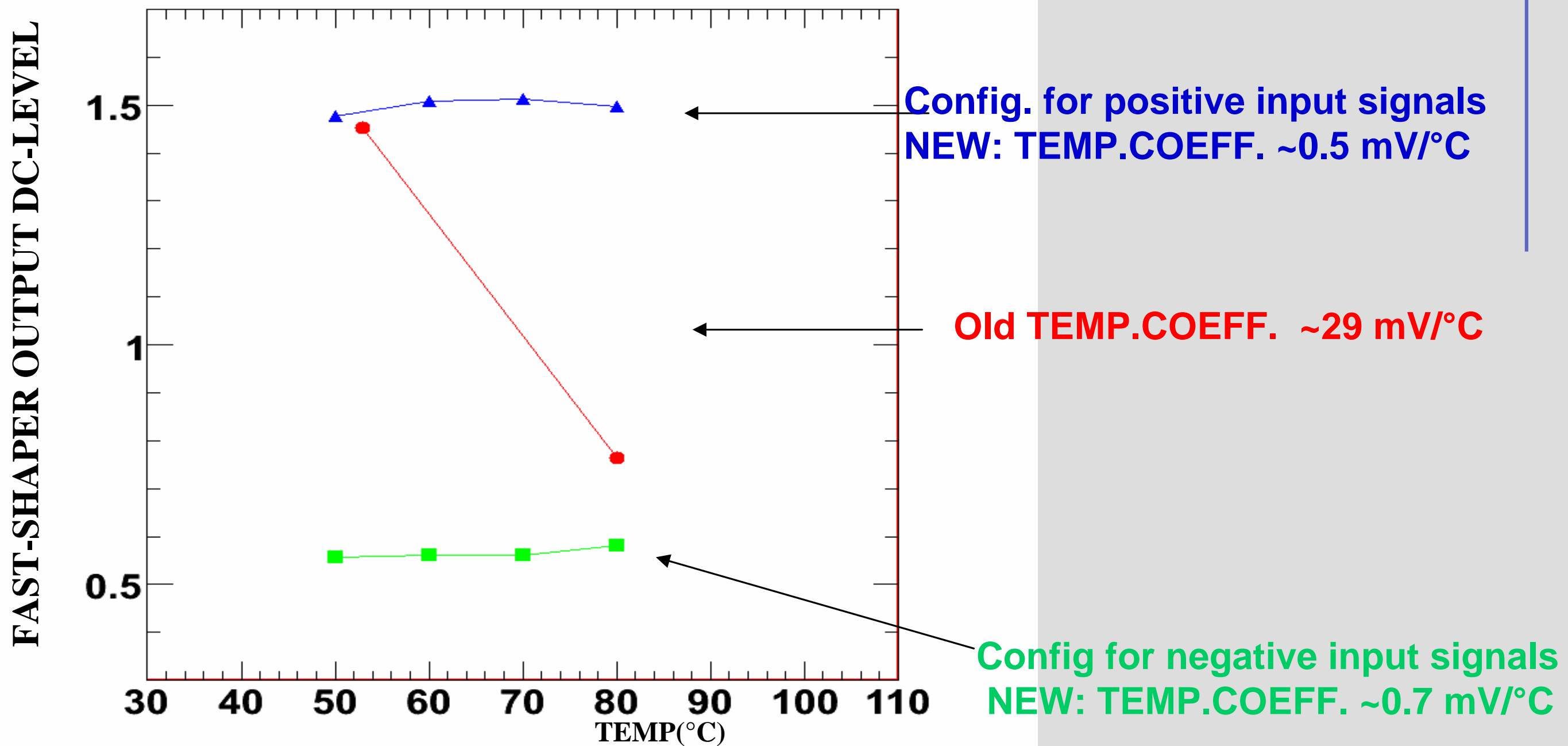
TYPICAL RESPONSE



Hans K.Soltveit, Physik. Inst. Heidelberg

Detectors for Super FRS, GSI, Feb. 11th 2009

TEMPERATURE SENSITIVITY



Hans K.Soltveit, Physik. Inst. Heidelberg

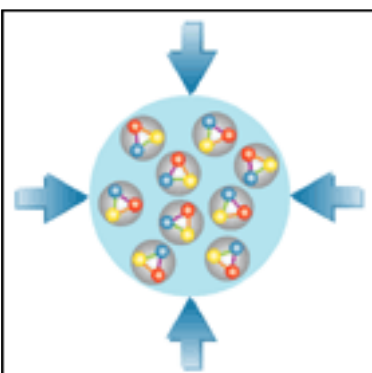
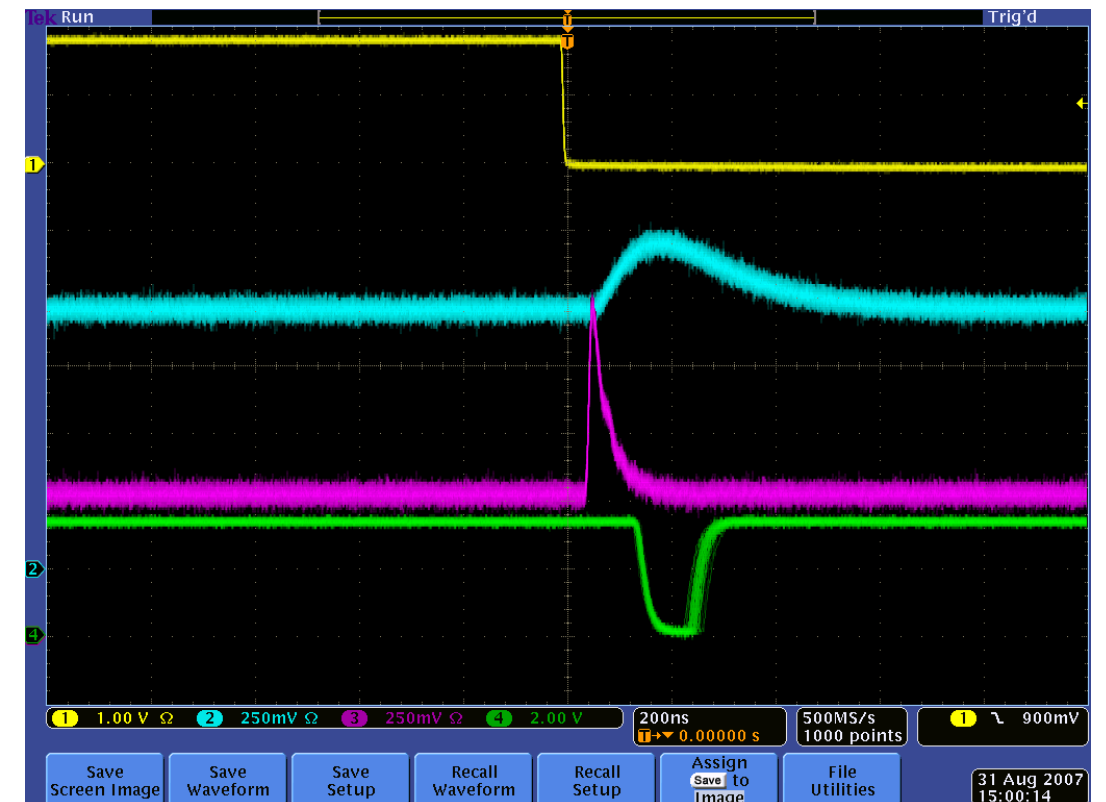
Detectors for Super FRS, GSI, Feb. 11th 2009



Midterm and Beyond, the CBM-XYTER

A dedicated *CBM-XYTER* development gets on its rails...

- Exploit detector prototyping experiences
- Self triggered architecture
- Rates adapted
- Radiation hard
- On chip energy conversion
- Efficient, low lead-count serialized data transfer
- DC-coupled double-sided Silicon readout



Dedicated XYTER Development for FAIR

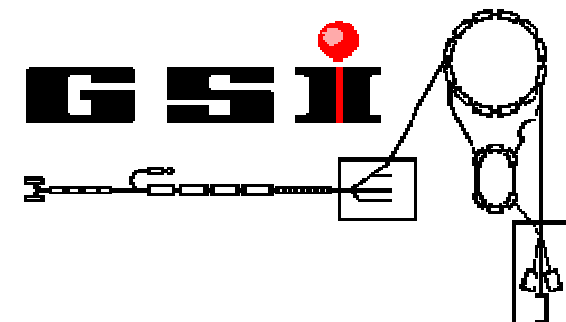
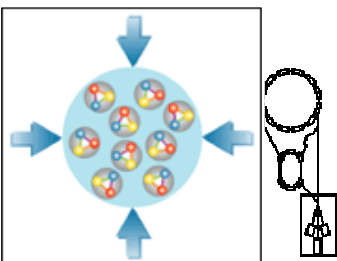
Generic n-XYTER architecture finds broad applications within FAIR:
CBM Silicon Strips STS, PANDA High Rate GEM TPC as well as
large area gas detectors (micro structures or wire chambers)

Twin chip development with XYTER architecture and diversities for:

Silicon Strip MIP detection with
time over threshold analogue
architecture

TRD electronics:
Larger dynamic range,
ion tail cancellation specialties

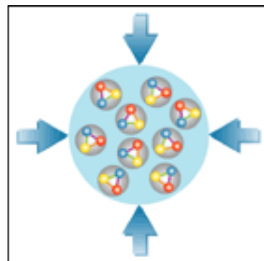
- Radiation hard design in UMC 0,180 μm (better than 10 MRad)
- Minimized power consumption
- Integration of modern, low power ADC on chip \rightarrow purely digital interface
- Highly multiplexed data interface (minimize cableing)
- Optimized system synchronization capabilities
- SEU tolerance
- Detector DC coupling capability
- Dense mounting capability



CBM-XYTER Family Planning

■ CBM-STS-XYTER

- minimize power
- realize dc-leakage compensation
- compact, high channel density
- MIP sensitivity in Si
- dense mounting



MUCH needs are somewhere in between. Preferably adopt these specs within one of the two!

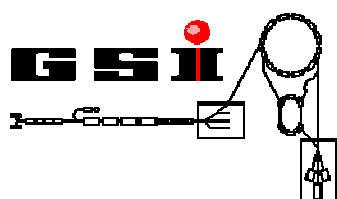
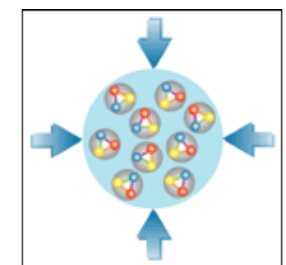
■ CBM-TRD-XYTER

- high resolution needs (8 to 9 bit)
- lower channel density
- next neighbor forced trigger logic?
- ion tail cancellation facilities
- baseline restoration
- lower occupancy

Both XYTER chips will employ common rad. hard library and common design blocks for the readout FiFo and MUX (data sparcification and de-randomization), slow control interface, data transfer serializers, testability features and clocking and time stamp generation.

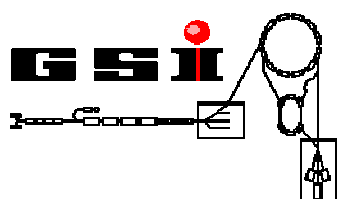
CBM-STS-XYTER

- Robert Szczygiel and Pawel Grybos (AGH Krakow) will realize the job. (They share experience on the n-XYTER development within DETNI)
- Pre-study ongoing
- MIP sensitivity with around 120 000 e dynamic range
- 128 channels, high density
- Time over threshold (TOT) architecture
 - extremely power saving due to less architectural overhead
 - low resolution needs, 4 to 5 bit
 - low demand on silicon real estate
- Particular demands on S/N for clean discrimination



CBM-TRD-XYTER

- Peter Fischer et al. (ZITI Heidelberg) embarked on the realization of this chip,
- specific architectural needs for the TRD-XYTER have not entirely crystallized yet.
- Concerted workshop on FEE needs in Dec. 2008
 - with detector physicists
 - and electronics engineers to work out the TRD-XYTER spec-frame



Assessment of specifications ongoing since Dec. 08

	STS	TRD	RICH	MUCH	PANDA MVD	PANDA GEM	PANDA TPC	NUSTAR ?
#channels/chip	128?	8-16?	128?	128 or 64	64 - 256, def.:128	32-128	32-128	
#channels in system	1.5M			200k-1000k/?	700k	100k	100k	
#chips in system	12k			n_ch_sys/n_ch_chip	5k		32k-8k	
power limit/channel				1W/128 chan??	1W/128channels	10mW	10mW	
noise limit				~1500 electrons (sigma)		500e-	500 e-	
max. rad. dose				100 krad ?		100krad		
avg. detector cap.	35pF			10 pF	10pF		7pF	
max. detector cap.				50 pF	50pF	2/300pF	7pF	
event rate	<=10MHz			< 10 MHz	<=10MHz		2.5 MHz	
hits/event	1000			1000/chamber ~3 ch per hit				
max. hit-rate/channel	150kHz		250kHz?	250kHz	40kHz	4..11/200kHz	200kHz	
average signal ampl.	~4fC	20fC		150-300 ke		15fC	4fC	
signal distribution	Landau	exp.	exp.?	mix Landau and Exp.		Landau	Landau	
measured quality	spat. res.	spat. res.	hit/no hit	spat. res.	spat. res + dE/dx	spat. res.	spat. res & hit time	
signal shape				dep. on det. type			rect. 30-40 ns	
max. poss. signal	some MIPs	20fC * 10		2-4Me	169ke	200ke	120fC	
ADC res./amplitude				7 -8 bit			0.8 fC	
Time resolution						10ns/hit	4ns/hit	
special tasks		baseline res.		spark prot.			spark prot.	

